

Notice of References Cited

Application/Control No.

10/526,115

Applicant(s)/Patent Under

Reexamination

KAARIO ET AL.

Examiner

Van Kim T. Nguyen

Art Unit

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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-7,258,276	08-2007	Linton et al.	235/385
*	B US-7,229,021	06-2007	Vesikivi et al.	235/462.01
*	C US-7,175,093	02-2007	Bridgelall, Raj	235/472.01
*	D US-7,020,685	03-2006	Chen et al.	709/204
*	E US-6,989,750	01-2006	Shanks et al.	340/572.4
*	F US-6,928,486	08-2005	Ono, Hiroshi	709/246
*	G US-6,843,415	01-2005	Vogler, Hartmut K.	235/385
*	H US-6,563,417	05-2003	Shaw, David A.	340/10.1
*	I US-5,864,765	01-1999	Barvesten, Mats O.	455/565
*	J US-2003/0095032	05-2003	Hoshino et al.	340/5.92
*	K US-2002/0116268	08-2002	Fukuda, Kunio	705/14
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
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T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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